

<b>Notice of References Cited</b>	Application/Control No. 09/929,323	Applicant(s)/Patent Under Reexamination CHONG ET AL	
	Examiner Hable Mered	Art Unit 2662	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,836,505	10-2003	Wang et al.	370/352
	B	US-2002/0004935	01-2002	Huotari et al.	717/11
	C	US-2001/0019559	09-2001	Handler et al.	370/468
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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	J	US-			
	K	US-			
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	M	US-			

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	Examiner Habte Mered	Art Unit 2662	Page 1 of 1

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	Examiner Habte Mered	Art Unit 2662	Page 1 of 1

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